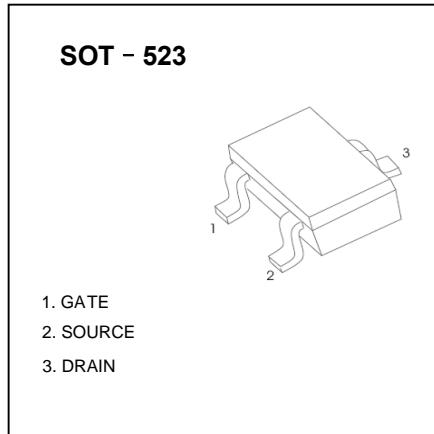
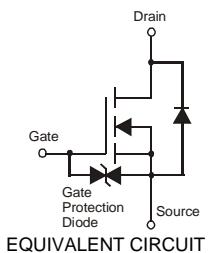


Plastic-Encapsulate MOSFETS

N-CHANNEL ENHANCEMENT MODE MOSFET

Features

- Low On-Resistance
- Low Gate Threshold Voltage
- Low Input Capacitance
- Fast Switching Speed
- Low Input/Output Leakage
- Lead Free By Design/RoHS Compliant (Note 2)
- ESD Protected up to 2kV



Marking Code: NA1

Maximum Ratings @ $T_A = 25^\circ\text{C}$ unless otherwise specified

Characteristic		Symbol	Value	Units
Drain-Source Voltage		V_{DSS}	20	V
Gate-Source Voltage		V_{GSS}	± 6	V
Continuous Drain Current (Note 1)	Steady State	I_D	0.63 0.45	A
Pulsed Drain Current		I_{DM}	6	A

Thermal Characteristics @ $T_A = 25^\circ\text{C}$ unless otherwise specified

Characteristic	Symbol	Value	Units
Total Power Dissipation (Note 1)	P_D	0.28	W
Thermal Resistance, Junction to Ambient	R_{JJA}	452	$^\circ\text{C}/\text{W}$
Operating and Storage Temperature Range	T_J, T_{STG}	-55 to +150	$^\circ\text{C}$

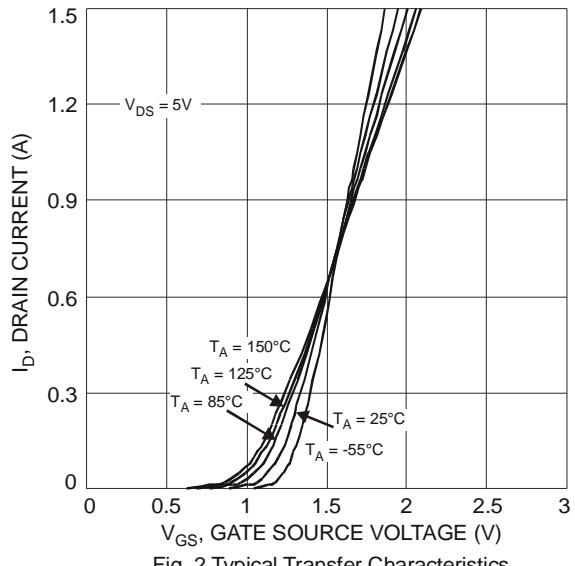
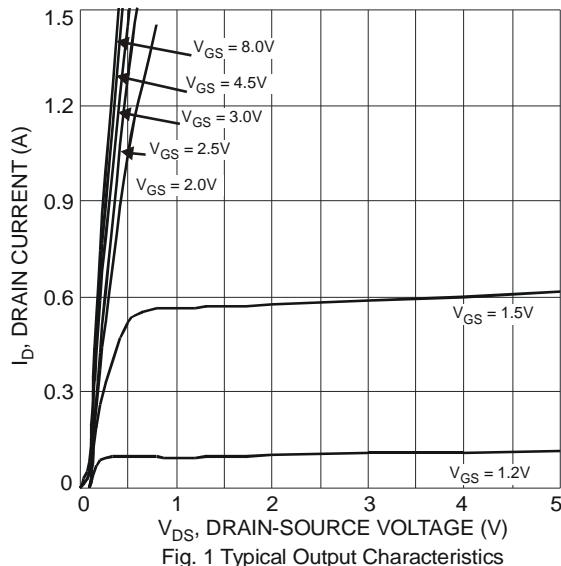
Notes:

1. Device mounted on FR-4 PCB.
2. No purposefully added lead.

Electrical Characteristics @ $T_A = 25^\circ\text{C}$ unless otherwise specified

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 4)						
Drain-Source Breakdown Voltage	BV_{DSS}	20	-	-	V	$\text{V}_{\text{GS}} = 0\text{V}, \text{I}_D = 250\mu\text{A}$
Zero Gate Voltage Drain Current $T_J = 25^\circ\text{C}$	I_{DSS}	-	-	100	nA	$\text{V}_{\text{DS}} = 20\text{V}, \text{V}_{\text{GS}} = 0\text{V}$
Gate-Source Leakage	I_{GSS}	-	-	± 1.0	μA	$\text{V}_{\text{GS}} = \pm 4.5\text{V}, \text{V}_{\text{DS}} = 0\text{V}$
ON CHARACTERISTICS (Note 4)						
Gate Threshold Voltage	$\text{V}_{\text{GS}(\text{th})}$	0.5	-	1.0	V	$\text{V}_{\text{DS}} = \text{V}_{\text{GS}}, \text{I}_D = 250\mu\text{A}$
Static Drain-Source On-Resistance	$\text{R}_{\text{DS}(\text{ON})}$	-	0.3	0.4	Ω	$\text{V}_{\text{GS}} = 4.5\text{V}, \text{I}_D = 600\text{mA}$
			0.4	0.5		$\text{V}_{\text{GS}} = 2.5\text{V}, \text{I}_D = 500\text{mA}$
			0.5	0.7		$\text{V}_{\text{GS}} = 1.8\text{V}, \text{I}_D = 350\text{mA}$
Forward Transfer Admittance	$ Y_{\text{fs}} $	-	1.4	-	S	$\text{V}_{\text{DS}} = 10\text{V}, \text{I}_D = 400\text{mA}$
Diode Forward Voltage (Note 4)	V_{SD}		0.7	1.2	V	$\text{V}_{\text{GS}} = 0\text{V}, \text{I}_S = 150\text{mA}$
DYNAMIC CHARACTERISTICS						
Input Capacitance	C_{iss}	-	60.67	-	pF	$\text{V}_{\text{DS}} = 16\text{V}, \text{V}_{\text{GS}} = 0\text{V}, f = 1.0\text{MHz}$
Output Capacitance	C_{oss}	-	9.68	-	pF	
Reverse Transfer Capacitance	C_{rss}	-	5.37	-	pF	
Total Gate Charge	Q_g	-	736.6	-	pC	$\text{V}_{\text{GS}} = 4.5\text{V}, \text{V}_{\text{DS}} = 10\text{V}, \text{I}_D = 250\text{mA}$
Gate-Source Charge	Q_{gs}	-	93.6	-	pC	
Gate-Drain Charge	Q_{gd}	-	116.6	-	pC	
Turn-On Delay Time	$t_{\text{D}(\text{on})}$	-	5.1	-	ns	$\text{V}_{\text{DD}} = 10\text{V}, \text{V}_{\text{GS}} = 4.5\text{V}, \text{R}_L = 47\Omega, \text{R}_G = 10\Omega, \text{I}_D = 200\text{mA}$
Turn-On Rise Time	t_r	-	7.4	-	ns	
Turn-Off Delay Time	$t_{\text{D}(\text{off})}$	-	26.7	-	ns	
Turn-Off Fall Time	t_f	-	12.3	-	ns	

Notes: 4. Short duration pulse test used to minimize self-heating effect.



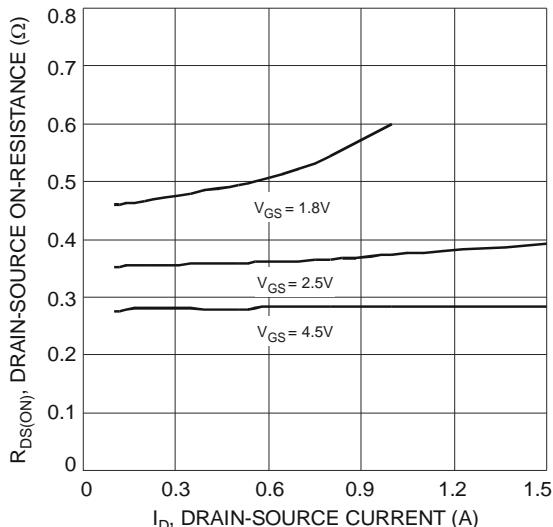


Fig. 3 Typical On-Resistance
vs. Drain Current and Gate Voltage

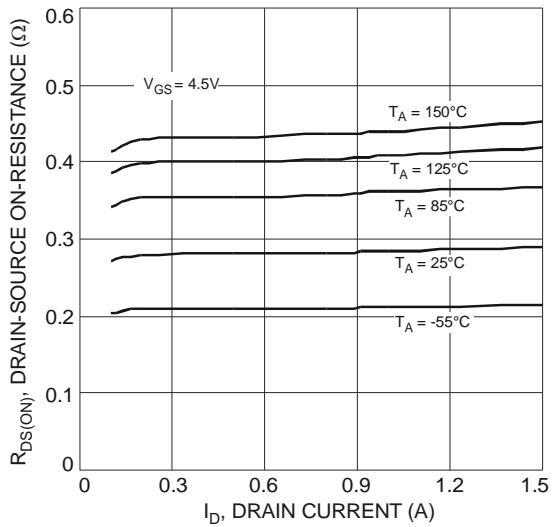


Fig. 4 Typical Drain-Source On-Resistance
vs. Drain Current and Temperature

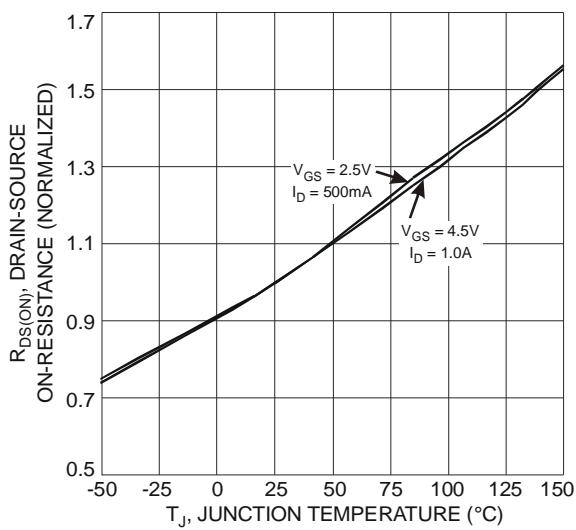


Fig. 5 On-Resistance Variation with Temperature

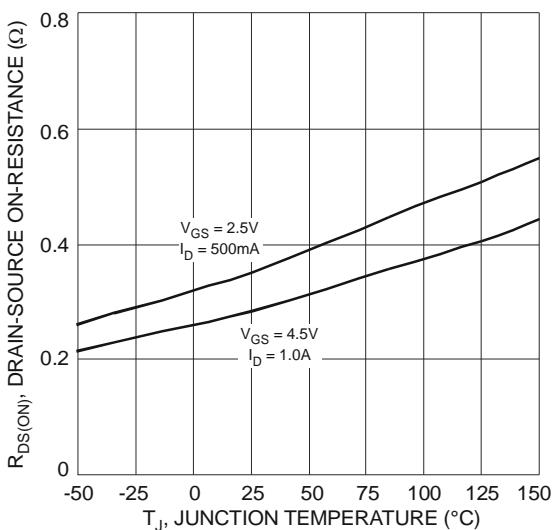


Fig. 6 On-Resistance Variation with Temperature

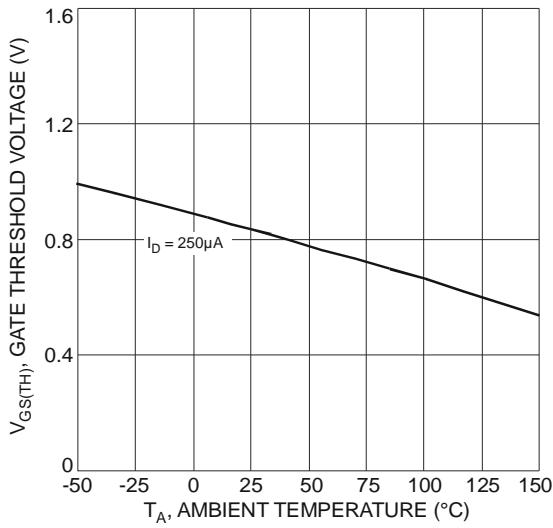


Fig. 7 Gate Threshold Variation vs. Ambient Temperature

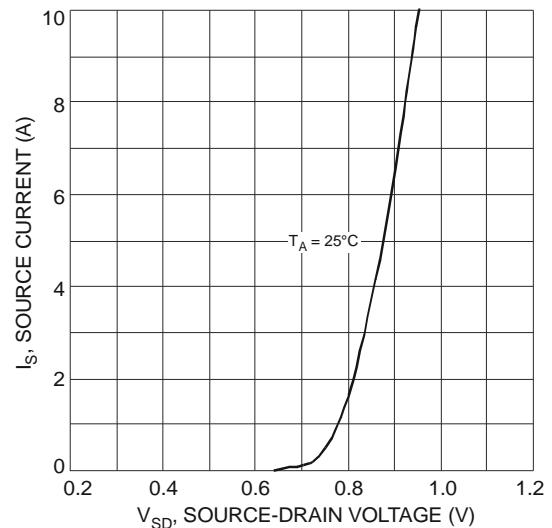


Fig. 8 Diode Forward Voltage vs. Current

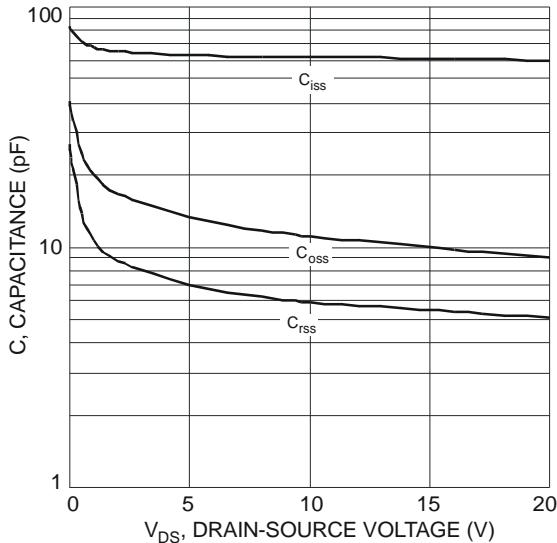


Fig. 9 Typical Capacitance

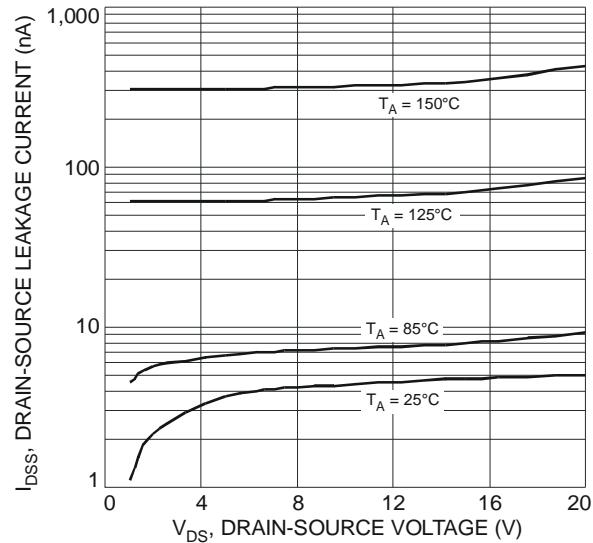


Fig. 10 Typical Drain-Source Leakage Current
vs. Drain-Source Voltage

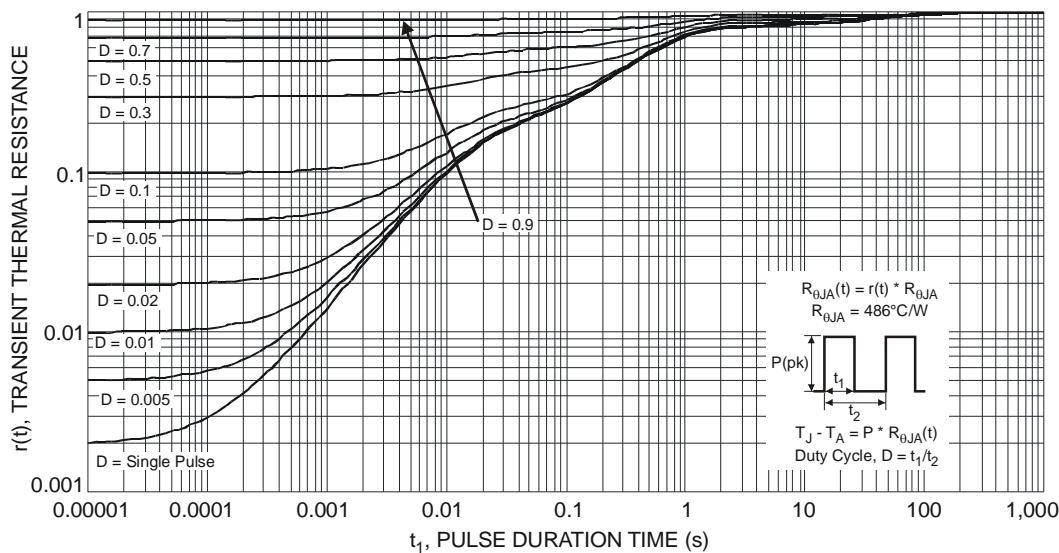


Fig. 11 Transient Thermal Response